



2nd IEEE International Conference on Design & Test of integrated micro & nano-Systems

June 7 - 10, 2020, Hammamet, Tunisia

General Chair

- Pr. Mohamed Masmoudi
ENIS, University of Sfax, Tunisia

Program Chairs

- Pr. Chokri Abdelmoula
ENET'COM-University of Sfax, Tunisia
- Pr. Smail Niar
LAMIH-University of Hauts-de-France, France

Topic Chairs

- Systems Design & Technology (SDT)**
Pr. Cherif Dridi, CRMN, Tunisia
Pr. Brahim Mezghani, ENIS, Tunisia
Pr. Ozcan Ozturk, Bilkent Univ., Turkey
Pr. Hasan Yantir, KAUST, KSA

Systems Testing & Reliability (STR)

- Dr. Salem Abdennadher, INTEL, USA
Pr. Fakhreddine Ghaffari, ENSEA, France
Dr. Arani Sinha, INTEL, USA

Nano Electronic Systems (NES)

- Pr. Kamel Besbes, CRMN, Tunisia
Pr. Federico Rosei, NanoFemtoLAB, Canada

VLSI IoT Devices (IoT)

- Pr. Abderrazek Jemai, INSAT, Tunisia
Pr. Baker Mohammad, Khalifa Univ., UAE
Pr. Fares Tounsi, ISIM, Tunisia

Plenary Session Chairs

- Pr. Mourad Loulou, ENIS, Tunisia
Pr. Hassen Mnif, ENETCOM, Tunisia

Tutorial Session Chairs

- Pr. Mourad Fakhfakh, ENETCOM, Tunisia
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Special Session Chairs

- Pr. Mohamed Abid, ENIS, Tunisia
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Panel Session Chair

- Pr. Ahmed Fakhfakh, ENETCOM, Tunisia

Workshops Chair

- Pr. Hatem Trabelsi, ENIS, Tunisia

Industrial Liaison Chairs

- Pr. Reda Nouacer, CEA, France
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Pr. Chiheb Rebai, SUPCOM, Tunisia

Publication Chairs

- Dr. Imen Barraj, ISIMG, Tunisia
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Local Arrangement Chair

- Dr. Amel Neifar, CRMN, Tunisia

Local Arrangement Members

- Dr. Karim Abbes, FSS, Tunisia
- Dr. Imen Barraj, ISIMG, Tunisia
- Dr. Ghazi Bouzid, FSS, Tunisia
- Mr. Nabil Ellouze, ENIS, Tunisia
- Dr. M. S. Masmoudi, ENET'COM, Tunisia
- Dr. Hassen Mestiri, FSM, Tunisia



Call for Panels

Aim of the Conference:

A panel proposal should address a related hot topic that is of substantial interest to the majority of DTS attendees, because it is controversial or increasing in importance. The proposal should include a panel title, introduction, the name of the organizer, a proposed moderator, and proposed panelists, along with contact information for all. For more information, please contact the Panel Chair.

The topic should be of sufficient relevance with respect to the general scope of the conference:

Systems Design & Technology (SDT)

- Analog, digital, mixed, and RF circuits design
- SoC, MPSoC, NoC, SIP, and NIP design
- Embedded electronics and System architecture
- MEMS, NEMS and MOEMS systems design
- Low-power electronics and systems design
- Sensory Systems Design
- Wireless communication systems design
- Opto-electronic System Design
- Biomedical Circuit & Systems
- Bio-engineering & Bio-chip design
- Linear & Non-Linear Circuits
- Power electronics and systems design
- Hardware co-design & FPGA design
- VLSI systems circuit and design
- DSPs and multiprocessor systems
- Embedded systems for Deep Learning
- Control Systems & Mechatronics
- Algorithms, methods and tools for modeling, simulation, synthesis and verification of ICs
- Algorithms, methods and tools for signal processing and image processing
- Algorithms, methods and tools for information security and cryptography
- Artificial Intelligence systems
- Electronic systems for energy harvesting applications
- GPS based engineering systems
- Process technologies, CMOS, BiCMOS, GaAs
- Microwave Systems & Integrated antenna
- 3D integration design and analysis
- ICs packaging

Systems Testing & Reliability (STR)

- Analog, digital, mixed, and RF circuits testing
- SoC, MPSoC, NoC, SIP, and NIP test
- On-line Testing and fault Tolerance
- Defect and Fault Modeling
- MEMS, NEMS and MOEMS Testing
- 3D testing
- Delay testing
- DFT, BIST and BISR
- Fault Simulation, ATPG
- Yield Optimization
- Memory & FPGA Test and Repair
- Automotive reliability and test
- Reliability failures and modeling
- Electronic System Reliability
- Test and Security Issues
- ATE issues
- Alternatives test strategies

Nano Electronic Systems (NES)

- Nanostructured / nanoporous Materials and devices
- Nano-circuits and Nano-architectures
- Nano-sensors and Actuators
- Nanorobotics and Nano-manipulation
- Modeling and Simulation at the Nanoscale
- Carbon Nanostructures and devices
- Microfluidics and Nanofluidics Systems
- 3D printing systems
- Polymer Nanotechnology
- Nanoscale Materials Characterization
- Sensors based on emerging devices
- Renewable Energy Technologies
- Smart Grid
- Measurement of health risk
- Aerospace and Vehicle Manufacturers

VLSI IoT Devices (IoT)

- Ultra-low power VLSI design for IoT
- System on Chip for IoTs
- IoT Application oriented Technologies
- IoT communication systems
- Real-time IoT systems
- RFID systems
- IoT Services and Applications
- IoT nodes architectures
- Sensors and Actuators for IoT
- Power and Energy systems design for IoT nodes
- Connectivity for IoT
- Computing Platforms for IoT
- Data Acquisition, Storage and Management for IoT
- Security and Privacy Enhancing Technologies for IoT devices
- IoT System Interfaces
- Reliability of IoT VLSI

Panel Chair:

- Pr. Ahmed Fakhfakh, ENETCOM, Tunisia

Upon acceptance, the organizer(s) will take care of preparing and submitting a one page abstract (to be included in the formal proceedings) covering the panel topic, coauthored by the organizer(s), the moderator and all panelists.

Deadline: Panels proposals due: **January 20th, 2020**

Conference Website: <http://www.DTS-conf.org>

